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Title of Change:	Gold to bare copper wire and Hitachi to Henkel mold compound conversion for Zener and ESD Protection devices assembled in ON Semiconductor Leshan facility.	
Proposed Changed Material First Ship Date:	03 May 2021 or earlier if approved by customer	
Current Material Last Order Date:	N/A Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.	
Current Material Last Delivery Date:	N/A The Current Material Last Delivery Date may be subject to change based on build and deplet of the current (unchanged) material inventory	
Product Category:	Active components – Discrete components	
Contact information:	Contact your local ON Semiconductor Sales Office or <u>Jim.Peng@onsemi.com</u>	
PCN Samples Contact:	 Contact your local ON Semiconductor Sales Office to place sample order or <pcn.samples@onsemi.com>.</pcn.samples@onsemi.com> Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements. 	
Sample Availability Date:	N/A	
PPAP Availability Date:	N/A	
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or ffvf9f@onsemi.com	
Type of Notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change or earlier upon customer approval. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact PCN.Support@onsemi.com.	
Change Category		
Category	Type of Change	
Process - Assembly	Change of mold compound, Change of wire bonding	

Description and Purpose:

Upon the expiration of this PCN, these devices will be built with 0.8mils bare copper wire and Henkel GR640 HV mold compound at the same site. Datasheet specifications and product electrical performance remain unchanged. Reliability qualification and full electrical characterization over temperature has been performed.

The copper wire is with higher thermal conductivity and lower resistivity which benefits for customer application. Henkel mold compound has better property to improve package encapsulation performance. This is to unify the wire material in process also. There is no change in the fit, form or functions of the affected OPNs.

Material to be change	Before Change Description	After Change Description
Bond Wire	0.8 mils gold wire	0.8 mils bare copper wire
Mold Compound	Hitachi GE200F	Henkel GR640 HV

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Reason /	Motivation for Change:	Process/Materials Change				
unction,	ed impact on fit, form, reliability, product manufacturability:	The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded.				
		No anticipated impacts.	No anticipated impacts.			
Sites Affe	cted:					
ON Semic	onductor Sites		External Foundry/Subcon Sites			
eshan Pho.	penix Semiconductor, China		None			
Marking c Change:	of Parts/ Traceability of	Assembly Date Code				
Reliability	y Data Summary:					
RMS: 4553						
Package: S	C-70	Condit	ion	Interval	Results	
		Condit		Interval Before TC, UHAST, HAST, IOL	Results 0/231	
Package: So Test	C-70 Specification		260 °C	Interval Before TC, UHAST, HAST, IOL 96 hrs		
Package: So Test PC	C-70 Specification JESD22-A113	MSL 1@	260 °C no bias, 96 hrs	Before TC, UHAST, HAST, IOL	0/231	
Package: So Test PC UHAST	C-70 Specification JESD22-A113 JESD22 A118	MSL 1 @ Ta=130C, 85% RH,	260 °C no bias, 96 hrs o +150°C	Before TC, UHAST, HAST, IOL 96 hrs	0/231 0/231	
Package: So Test PC UHAST TC	C-70 Specification JESD22-A113 JESD22 A118 JESD22-A104	MSL 1@ Ta=130C, 85% RH, Ta= - 65°C tr	260 °C no bias, 96 hrs o +150°C or 42V max, 192 hours.	Before TC, UHAST, HAST, IOL 96 hrs 2000 cyc	0/231 0/231 0/231	
Package: So Test PC UHAST TC HAST	C-70 Specification JESD22-A113 JESD22 A118 JESD22-A104 JESD22 A110	MSL 1 @ Ta=130C, 85% RH, Ta= - 65°C to 130C/85%RH, 80% rated V	260 °C no bias, 96 hrs o +150°C or 42V max, 192 hours. D°C, On/off = 2 min	Before TC, UHAST, HAST, IOL 96 hrs 2000 cyc 192 hrs	0/231 0/231 0/231 0/231 0/231	
Package: So Test PC UHAST TC HAST IOL	C-70 Specification JESD22-A113 JESD22 A118 JESD22-A104 JESD22 A110 MIL-STD-750 (M1037)	MSL 1 @ Ta=130C, 85% RH, Ta= - 65°C to 130C/85%RH, 80% rated V Ta=+25°C, delta Tj=100	260 °C no bias, 96 hrs o +150°C or 42V max, 192 hours. 0°C, On/off = 2 min ated V, 1008 Hrs	Before TC, UHAST, HAST, IOL 96 hrs 2000 cyc 192 hrs 30000 cyc	0/231 0/231 0/231 0/231 0/231	
Package: So Test PC UHAST TC HAST IOL HTRB	C-70 Specification JESD22-A113 JESD22 A118 JESD22-A104 JESD22 A110 MIL-STD-750 (M1037) MIL-STD750-1	MSL 1 @ Ta=130C, 85% RH, Ta= - 65°C to 130C/85%RH, 80% rated V Ta=+25°C, delta Tj=100 Tj= max, V=100% ra	260 °C no bias, 96 hrs o +150°C or 42V max, 192 hours. D°C, On/off = 2 min ated V, 1008 Hrs bias,2016hours	Before TC, UHAST, HAST, IOL 96 hrs 2000 cyc 192 hrs 30000 cyc 1008 hrs	0/231 0/231 0/231 0/231 0/231 0/231 0/231	
Package: So Test PC UHAST TC HAST IOL HTRB HTSL RSH	C-70 Specification JESD22-A113 JESD22 A118 JESD22 A118 JESD22 A110 MIL-STD22 A110 MIL-STD750-1 JEDS22- A103 JESD22- B106 Ste Device: SESD9L3.3ST5G 7 OD-923	MSL 1 @ Ta=130C, 85% RH, Ta= - 65°C tr 130C/85%RH, 80% rated V Ta=+25°C, delta Tj=100 Tj= max, V=100% ra Temp.=150°C, no b Ta = 265C,	260 °C no bias, 96 hrs o +150°C or 42V max, 192 hours. O°C, On/off = 2 min ated V, 1008 Hrs bias,2016hours 10 sec	Before TC, UHAST, HAST, IOL 96 hrs 2000 cyc 192 hrs 30000 cyc 1008 hrs 2016 hrs -	0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/30	
Package: So Test PC UHAST TC HAST IOL HTRB HTRB HTSL RSH Qual Vehic RSS: 4269	C-70 Specification JESD22-A113 JESD22 A118 JESD22 A118 JESD22 A110 MIL-STD-750 (M1037) MIL-STD750-1 JEDS22- A103 JESD22- B106 Cle Device: SESD9L3.3ST5G 7	MSL 1 @ Ta=130C, 85% RH, Ta= - 65°C to 130C/85%RH, 80% rated V Ta=+25°C, delta Tj=100 Tj= max, V=100% ra Temp.=150°C, no b Ta = 265C,	260 °C no bias, 96 hrs o +150°C or 42V max, 192 hours. D°C, On/off = 2 min ated V, 1008 Hrs bias,2016hours	Before TC, UHAST, HAST, IOL 96 hrs 2000 cyc 192 hrs 30000 cyc 1008 hrs	0/231 0/231 0/231 0/231 0/231 0/231 0/231	

Test	Specification	Condition	Interval	Results
PC	JESD22-A113	MSL 1 @ 260 °C	Before TC, UHAST, HAST, IOL	0/231
UHAST	JESD22 A118	Ta=130C, 85% RH, no bias, 96 hrs	96 hrs	0/231
тс	JESD22-A104	Ta= - 65°C to +150°C	2000 cyc	0/231
HAST	JESD22 A110	130C/85%RH, 80% rated V or 42V max, 192 hours.	192 hrs	0/231
IOL	MIL-STD-750 (M1037)	Ta=+25°C, delta Tj=100°C, On/off = 2 min	30000 cyc	0/231
HTRB	MIL-STD750-1	Tj= max, V=100% rated V, 1008 Hrs	1008 hrs	0/231
HTSL	JEDS22- A103	Temp.=150°C,no bias,2016hours	2016 hrs	0/231
RSH	JESD22- B106	Ta = 265C, 10 sec	-	0/30



NOTE: AEC 1 Pager attached

To view attachments:

- 1. Download pdf copy of the PCN to your computer
- 2. Open the downloaded pdf copy of the PCN
- 3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field
- 4. Then click on the attached file/s

Electrical Characteristics Summary:

Electrical characteristics are not impacted.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the **PCN Customized Portal**.

Current Part Number	New Part Number	Qualification Vehicle
SZMMBZ27VAWT1G	NA	SZMMBZ27VAWT1G
SZNZ9F6V8ST5G	NA	SESD9L3.3ST5G